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	W	TITLE: Built-In Test Sequence Generation for Synchronous Sequential Circuits Based on Loading and Expansion of Test Subsequences, author: Pomeranz et al, ACM, 1999.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.